

## Reliability Monitoring Results

**Quarters:** Q1/2022 to Q4/2022

Based on structural similarity

Supplier		User Part Number				
Nexperia B.V.		74ALVC00BQ				
Part Description: Quad 2-input NAND gate						
Function Family: ALVC Process family: Sub micron Package family: DHVQFN						
JESD47 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	TEST Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 2	PC Preconditioning	JESD22-A113 MSL 1	N/A	386	23019	0
# 5a	HTOL EFR High Temperature Operating Life Extrinsic	JESD22-A108 Tj = 150°C VCCMAX ≤ V ≤ 1.2*VCCMAX	48 hours or 168 hours	132	33268	0
# 5b	HTOL IFR High Temperature Operating Life Intrinsic	JESD22-A108 Tj = 150°C VCCMAX ≤ V ≤ 1.2*VCCMAX	≥500 hours	89	7065	0
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	208	12655	0
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = VCCMAX	96 hours	178	10364	0

### Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above)

Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic (HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Product Family	Package Family	Quantity	Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
ALVC	DHVQFN	7065	0	28	0.5	2.07 E+09